

Notice of References Cited	Application/Control No. 10/611,623	Applicant(s)/Patent Under Reexamination HSIAO ET AL.	
	Examiner Paul D Kim	Art Unit 3729	Page 1 of 1

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	C	US-6,221,559	04-2001	Lee et al.	430/311
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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.